1-LINE TO 6-LINE CLOCK DRIVER WITH SELECTABLE POLARITY AND 3-STATE OUTPUTS

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- Low Output Skew for Clock-Distribution and Clock-Generation Applications
- TTL-Compatible Inputs and Outputs
- Distributes One Clock Input to Six Clock Outputs
- Polarity Control Selects True or Complementary Outputs
- Distributed V_{CC} and GND Pins Reduce Switching Noise
- High-Drive Outputs (-48-mA I_{OH}, 48-mA I_{OL})
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Packaged in Plastic Small-Outline Package

D PACKAGE (TOP VIEW)						
GND [4 2Y1 [4 2Y2 [6 GND [7	1 2 3 4 5 6 6 7	14 13 12	1Y1 1T/C V_CC 2T/C A V_CC 3T/C			

description

The CDC391 contains a clock-driver circuit that distributes one input signal to six outputs with minimum skew for clock distribution. Through the use of the polarity-control (\overline{T}/C) inputs, various combinations of true and complementary outputs can be obtained. The output-enable (\overline{OE}) input is provided to disable the outputs to a high-impedance state.

The CDC391 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

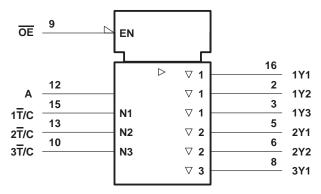
INPUTS			OUTPUT
OE	T/C	Α	Υ
Н	Х	Χ	Z
L	L	L	L
L	L	Н	Н
L	Н	L	Н
L E.O	Н	Н	L

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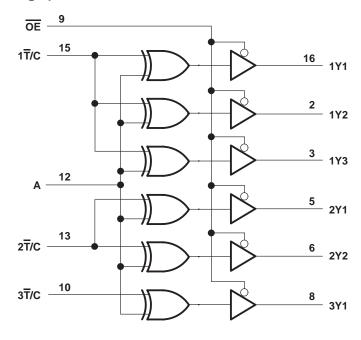


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high state or power-off state, VO	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Current into any output in the low state, I _O	96 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	0.77 W
Storage temperature range, T _{stq}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 300 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*, literature number SCBD002B.

recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
Vсс	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
٧ı	Input voltage	0		VCC	V
loh	High-level output current			-48	mA
IOL	Low-level output current			48	mA
$\Delta t/\Delta v$	Input transition rise or fall rate			5	ns/V
f _{clock}	Input clock frequency			100	MHz
T _A	Operating free-air temperature	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP‡	MAX	UNIT
V_{IK}	$V_{CC} = 4.75 \text{ V},$	$I_{I} = -18 \text{ mA}$				-1.2	V
Voн	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -48 \text{ mA}$		2			V
V _{OL}	$V_{CC} = 4.75 V$,	$I_{OL} = 48 \text{ mA}$				0.5	V
lį	V _{CC} = 5.25 V,	$V_I = V_{CC}$ or GND				±1	μΑ
loz	V _{CC} = 5.25 V,	$V_O = V_{CC}$ or GND		T		±50	μΑ
ΙΟ§	V _{CC} = 5.25 V,	V _O = 2.5 V		-15		-100	mA
			Outputs high			10	
ICC	$V_{CC} = 5.25 \text{ V},$ $V_{I} = V_{CC} \text{ or GND}$	$I_{O} = 0$,	Outputs low			40	mA
	AL = ACC OLOUD	Outputs disabled				10]
C _i	V _I = 2.5 V or 0.5 V	·	·		3		pF
Со	V _O = 2.5 V or 0.5 V		·		5		pF

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

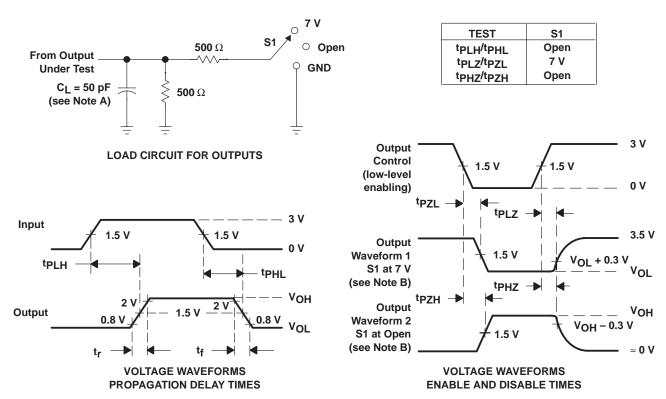
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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
t _{PLH}	A	Any Y	1.5	5	ns
t _{PHL}	^		1.5	5	115
t _{PLH}	- T/C	Any Y	1.5	5	ns
tPHL		Ally f	1.5	5	
^t PZH	ŌĒ	Any Y	1.5	5	20
tPZL		Any f	3	7	ns
t _{PHZ}		Any Y		5	ns
tPLZ	ŌĒ			5	
+	А	Any Y (same phase)		0.5	ns
^t sk(o)		Any Y (any phase)		1	
tsk(p)	А	Any Y		1	ns
t _r				1.5	ns
t _f				1.5	ns

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PARAMETER MEASUREMENT INFORMATION



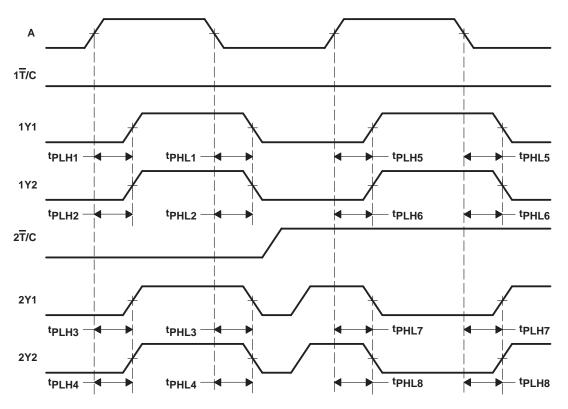
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2.5 \text{ ns.}$ tf \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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PARAMETER MEASUREMENT INFORMATION



- NOTES: A. Output skew, $t_{SK(0)}$, from A to any Y (same phase), can be measured only between outputs for which the respective polarity-control inputs (\overline{T}/C) are at the same logic level. It is calculated as the greater of:
 - The difference between the fastest and slowest of tpLH from A↑ to any Y (e.g., tpLHn, n = 1 to 4; or tpLHn, n = 5 to 6)
 - The difference between the fastest and slowest of tp_{HL} from A↓ to any Y (e.g., tp_{HLn}, n = 1 to 4; or tp_{HLn}, n = 5 to 6)
 - The difference between the fastest and slowest of t_{PLH} from A↓ to any Y (e.g., t_{PLHn}, n = 7 to 8)
 - The difference between the fastest and slowest of tpHL from A↑ to any Y (e.g., tpHLn, n = 7 to 8)
 - B. Qutput skew, t_{sk(0)}, from A to any Y (any phase), can be measured between outputs for which the respective polarity-control inputs (T/C) are at the same or different logic levels. It is calculated as the greater of:
 - The difference between the fastest and slowest of tp_{LH} from A[↑] to any Y or tp_{HL} from A[↑] to any Y (e.g., tp_{LHn}, n = 1 to 4; or tp_{LHn}, n = 5 to 6, and tp_{HLn}, n = 7 to 8)
 - The difference between the fastest and slowest of tp_{HL} from A↓ to any Y or tp_{LH} from A↓ to any Y (e.g., tp_{HLn}, n = 1 to 4; or tp_{HLn}, n = 5 to 6, and tp_{LHn}, n = 7 to 8)

Figure 2. Waveforms for Calculation of tsk(o)

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